



Super RF tester

DELTA's latest investment in ATE equipment for advanced RF testing is the 93000 SOC test system from Agilent Technologies

Radio Modem IC tests

The Agilent 93000 model P1000 with RF measurement suite has all the capability necessary to meet the test requirements for the Bluetooth radio modem IC including:

- 8 GHz modulated stimulus
- 8 GHz measure
- Up to 12 RF ports
- Up to 1 Gbit/s. I/O data rate



93000 SOC Solution for RF / HF & Bluetooth

The agilent 93000 SOC Series

is our unique single scalable platform that combines the widest application coverage with full test capability in:

- Analog, RF, Digital
- Embedded memory and scan all at truly affordable price/performance points.

This allows us to test your most complex device with the highest throughput for the most economical price.

You also get unprecedented flexibility to evolve your device to the next application, to the next set of criteria fast, easy and affordable.

Baseband Controller IC tests

- Up to 1024 digital pins
- 1 Gbit/s I/O data rate
- 112 Mb of memory for every digital pin
- At speed embedded memory and scan test
- BIST control

Single Chip tests

The Agilent 93000 model P1000 with RF measurement suite has all the capability necessary to meet the total test requirements for a Bluetooth single chip solution.

Two test heads in one

Configuration management is essential to maintain high levels of utility and meet volume manufacturing cost goals.

The Agilent 93000 SOC Series is available with two test head sizes - 512-pin and 1024-pin - which are 100% compatible. A DUT board from the 512-pin head can be placed on the 1024-pin version.

This allows DELTA to minimise the capital cost of testers - as large and small test heads can be used on the manufacturing floor - and to maximise utilisation, further reducing Cost-of-Test.



Flexibility without compromise

The Agilent 93000 SOC series features third-generation gigabit technology and the true Test Processor-Per-Pin architecture is a key factor for cost effective volume testing of SOC devices.

This architecture has the capability to allow mixing channels of different speeds and segmenting of the system to address simultaneous testing of different ports at different speeds.

Test processor-Per-Pin architecture allows data rates of up to 1Gbps with vector generation on each pin without multiplexing and without compromising system performance or accuracy.

DELTA does full range test of analog applications

The Agilent 93000 SOC Series delivers what you need: Low-frequency modules to test 20-bit audio resolution for consumer products such as AC-97, High-frequency modules with over 100 MHz of analog bandwidth for applications like set-top box, and ultra high-frequency modules to address transceiver devices.

The full range of analog modules will cover applications of the future - such as WAP, xDSL, Internet and enterprise networks.

Test the Internet & more

The combination of leading digital capabilities and a broad range of analog modules positions the Agilent 93000 SOC series as a leader in communications ATE, also covering key applications ranging from mobile communications and enterprise networks to super-high-speed infrastructure.

Already established for SONET testing, the Agilent 93000 is positioned to address future silicon requirements such as SerDes with full parametric characterization and the fastest transition to lowest-cost high-volume production.

For further information please contact

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Brief list of DELTA equipment

Major facilities for microelectronic testing

Teradyne Catalyst	Mixed signal Testing for advanced ASICs/Super chips
Teradyne A585	Mixed Signal Testing for advanced ASICs
Teradyne J750	VLSI Digital Testing for high pin count (320 pins)
HP 83000C	VLSI Digital Testing
HP 93000	RF Tester
Trillium Arraymaster	VLSI Digital Testing with analog option
	ASICs, microprocessors, ECL devices, memories
TSSI - Summit	Test development software tools

Major facilities - Endurance testing

Loranger Sentry 9H	Dynamic burn-in chamber
Hereaus VMS 03	Temperature cycling chamber
Hirayama	HAST Testing - Pressure Cooker Test

Major facilities - Handling

Handlers	DIL 300', 400', 600', PLCC 44, QFP, SO 150,
	209, 300, QFP, PLCC, μBGA, BGA, TSOP, LCC, MLP, QFN
KLA 1007E	Wafer Prober - 4" and 6" wafer @ 25 - 125°C
A-PM-90A	Wafer Prober - 4", 6", 8" wafer @ 25 - 150°C

DELTA

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